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Application/Control No.	Applicant(s)/Patent under Reexamination
10/534,494	LEWIN ET AL.
Examiner	Art Unit

Patrick J. Lee

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SEARCHED					
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East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	9/14/2006	PL
East (see attached) - USPAT, US- PGPUB, EPO, JPO, DERWENT	9/25/2006	PL
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